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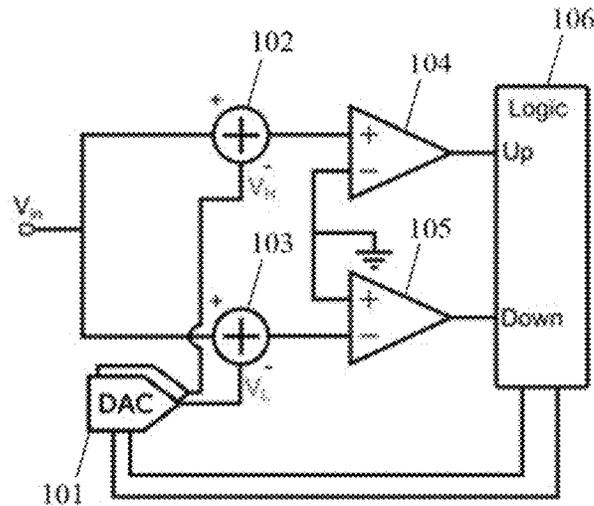


FIG. 1A (Prior Art)

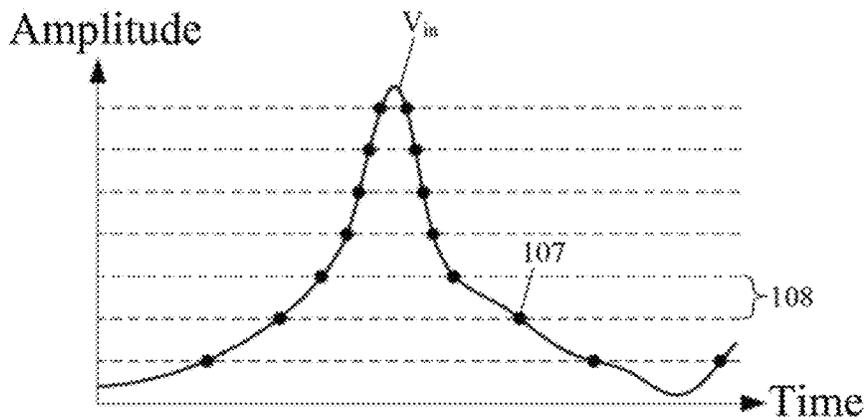


FIG. 1B (Prior Art)

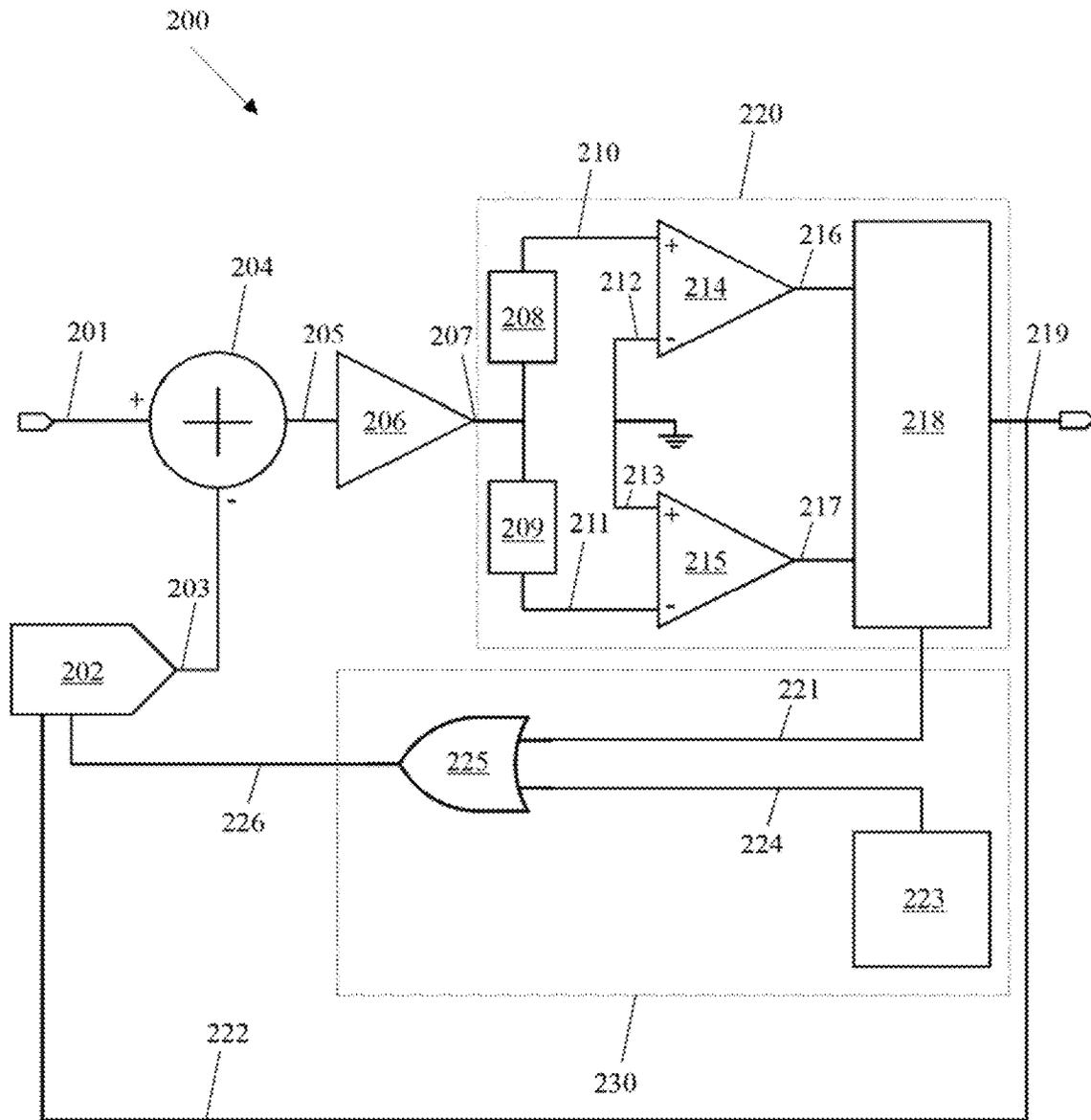


FIG. 2

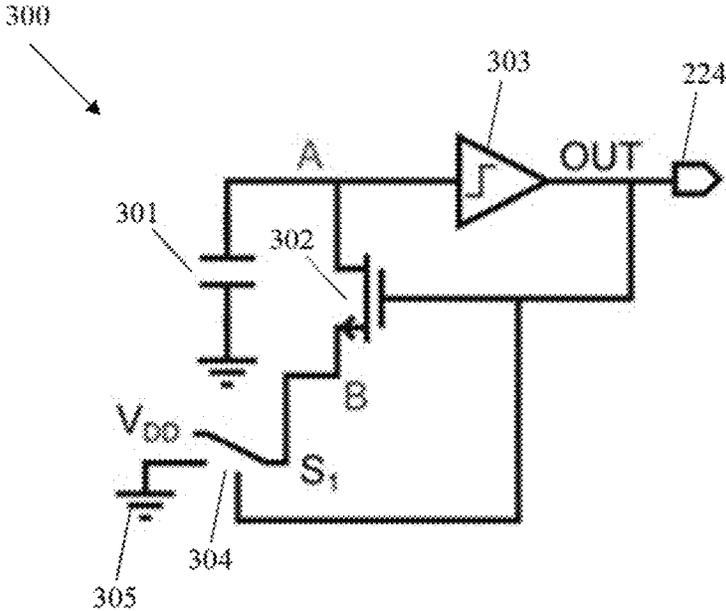


FIG. 3A

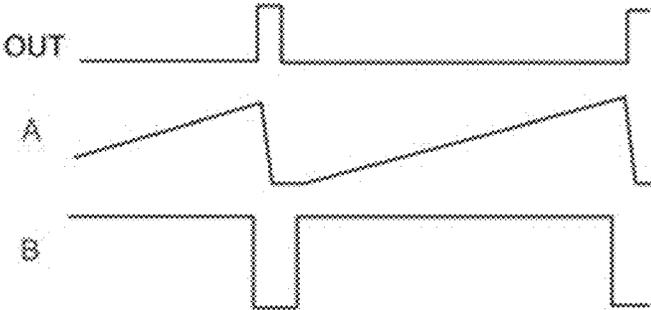


FIG. 3B

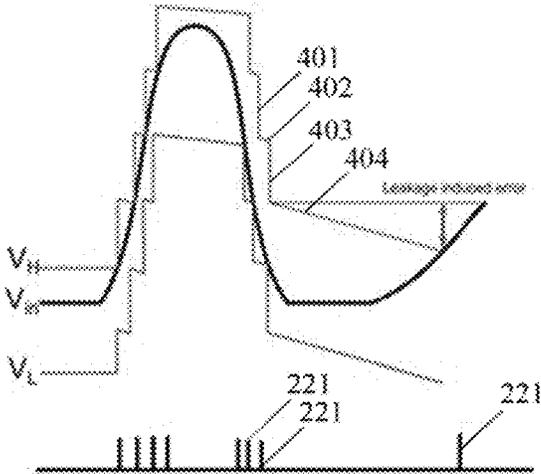


FIG. 4A

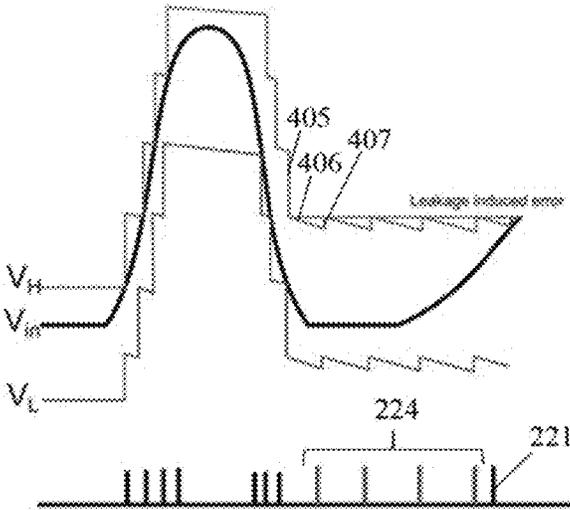


FIG. 4B

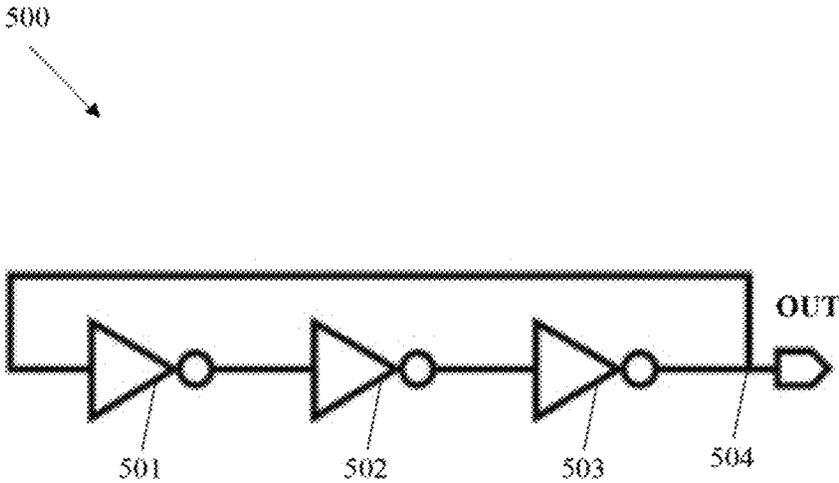


FIG. 5A



FIG. 5B

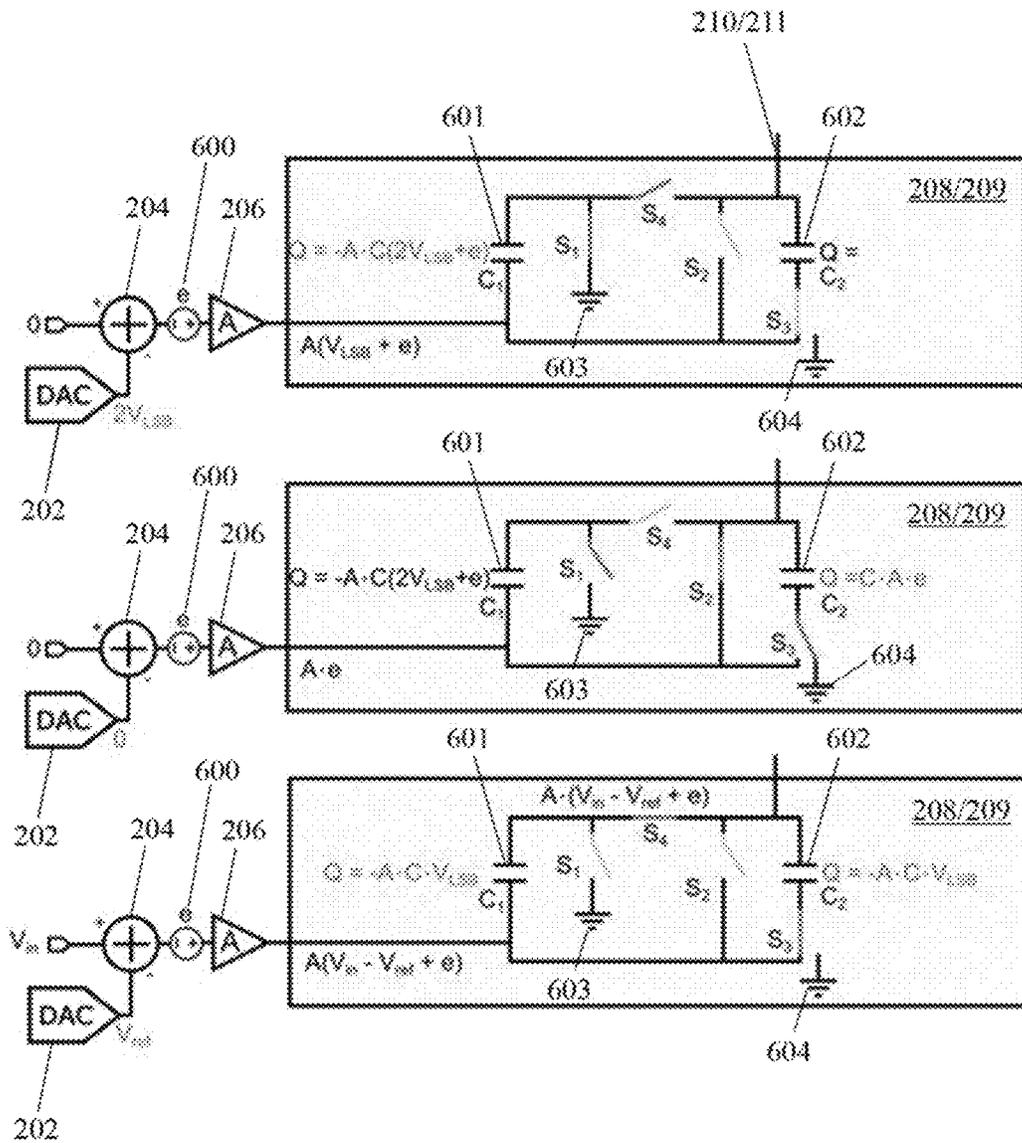


FIG. 6

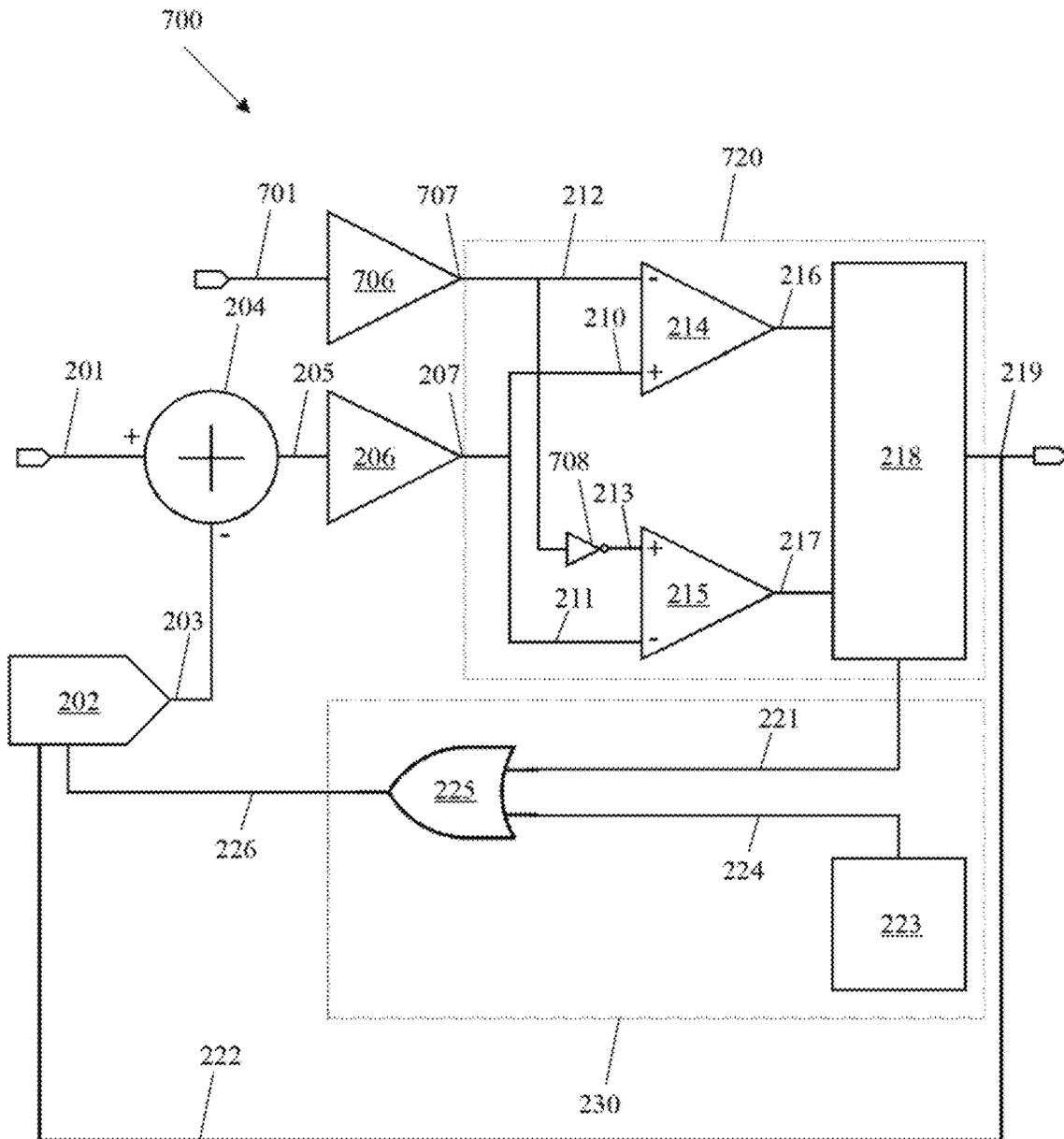


FIG. 7

800

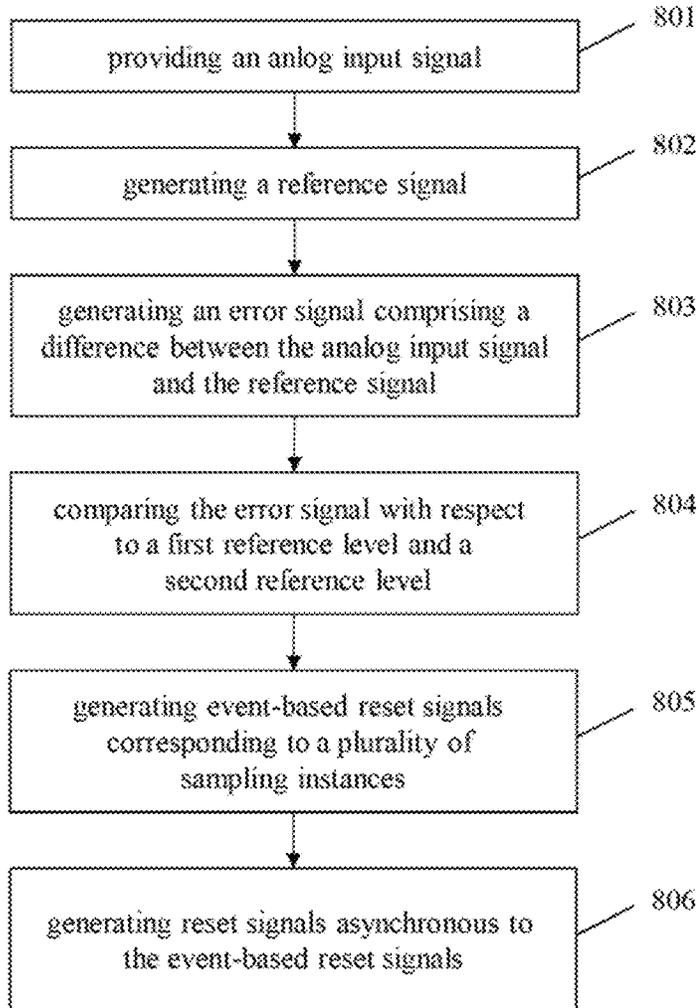


FIG. 8

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SYSTEM AND METHOD FOR ANALOG-TO-DIGITAL SIGNAL CONVERSION

CROSS-REFERENCE TO RELATED APPLICATIONS

The present application is a non-provisional patent application claiming priority to European Patent Application No. EP 21150013.7, filed Jan. 4, 2021, the contents of which are hereby incorporated by reference.

FIELD OF THE DISCLOSURE

The disclosure relates to analog-to-digital signal conversion, especially to asynchronous analog-to-spike converter architectures in wireless sensor nodes.

BACKGROUND

Generally, minimizing power consumption in wireless sensor nodes is important to ensure a long lifetime of the battery. One way to minimize the power consumption is by making the power consumption activity dependent. For many biological signals, such as ECG, EEG, neuron signals, only small pieces in time are important to process. This reduced data helps, for example, the transmitter, since it now may transmit less data and thus uses less power. Since the transmitter power consumption is usually much higher than other components such as the front-end, reducing the power of the transmitter has a significant impact on the total power consumption.

For a continuous monitoring system, the analog information is continuously monitored by a front-end, then converted by an analog-to-digital converter (ADC), and then sent out via a transmitter. Conventionally, an ADC samples the signal at every clock pulse, which is independent of the input signal. This means that even when the signal does not change, samples are still being generated. A different way of sampling is called level-crossing sampling, where a sampling instance occurs, i.e. the generation of a sample, only when the amplitude of the signal changed by a fixed step. The patent document U.S. Pat. No. 9,252,658 B2 shows such level-crossing based sampling, for instance.

Usually, two different comparators are used to compare against the reference level just above and below the signal level. However, the input referred offset of the comparators directly affects the achievable signal-to-noise-and-distortion ratio (SNDR). This means that to achieve high SNDR (e.g. >60 dB), the offset of the comparator should be kept low. Additionally, for low frequency, high SNR applications, the area of a level-crossing ADC can increase. This is due to the leakage in typical CMOS technologies. To meet the long hold time of the digital-to-analog converter (DAC) for low frequency signals, larger capacitors may be used. The increased area size can become a problem when, for instance, thousands of channels in the human body may be used to measure bio signals.

SUMMARY

Accordingly, the disclosure and the claims provide a system and a method for analog-to-digital signal conversion, which can address the above-mentioned limitations.

According to a first aspect of the disclosure, a system for analog-to-digital signal conversion is provided. The system comprises an analog input signal, a digital-to-analog con-

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verter configured to generate a reference signal, and an amplifier configured to amplify an error signal comprising a difference between the analog input signal and the reference signal. The system further comprises a level-crossing based sampling circuit comprising a first comparator configured to compare the error signal with respect to a first reference level, and a second comparator configured to compare the error signal with respect to a second reference level, thereby generating event-based reset signals corresponding to a plurality of sampling instances in order to reset the digital-to-analog converter and further to shift the first reference level and the second reference level through the digital-to-analog converter. Moreover, the system comprises a trigger circuit configured to generate reset signals asynchronous to the event-based reset signals in order to reset the digital-to-analog converter.

Therefore, the disclosure provides additional resets for resetting the DAC in addition to the event-based resets correspond to each sampling instances, i.e. to each instance of sample generation. The event-based reset signals or spikes reset the DAC and further change the reference signal level (e.g. voltage level) through the DAC, especially by shifting the first reference level and the second reference level via the DAC. Furthermore, the resets are not clock-generated so as to eliminate the necessity of having on-board oscillators.

Consequently, capacitors with increased area that are used for the DAC are not required even if the signal changes slowly, since the additional resets minimize the requirements for a longer hold time. Moreover, the amplifier, or a so-called pre-amplifier, shared by the comparators includes sufficient area for the calibration of the comparators. Any error made after the pre-amplifier is divided by the gain of the pre-amplifier, thereby relaxing the offset requirement of the comparators.

In some embodiments, the level-crossing based sampling circuit further includes a digital logic circuit configured to generate an amplitude and a time stamp corresponding to each of the plurality of sampling instances. In addition, the digital logic circuit is further configured to feedback the amplitude corresponding to each of the plurality of sampling instances to the digital-to-analog converter in order to generate the reference signal. In this regard, the digital logic circuit may comprise an up/down counter that functions as a digital integrator and a timer that records the time in-between two sampling instances or samples. For each sampling instances, the output of the comparators toggles and the digital logic circuit starts to update the up/down counter to refresh the comparison window.

In some embodiments, the digital-to-analog converter is a capacitive charge transfer digital-to-analog converter (e.g., a switched capacitor based digital-to-analog converter). In this regard, the trigger circuit comprises a switched capacitor arrangement in order to replicate the digital-to-analog converter. The use of capacitive DAC for reference signal or voltage generation may facilitate smaller area and low power consumption. Moreover, by replicating the DAC, e.g. replicating the switched-capacitor arrangement of the DAC, the leakage induced error of the DAC can be potentially measured during operation.

In some embodiments, the level-crossing based sampling circuit further comprises a first capacitor bank coupled between a common node downstream to the amplifier and the first comparator, where the first capacitor bank is configured to store the first reference level based on the reference signal. In addition, the level-crossing based sampling circuit further comprises a second capacitor bank coupled

between the common node downstream to the amplifier and the second comparator, where the second capacitor bank is configured to store the second reference level based on the reference signal.

In some embodiments, only one pre-amplifier is used to store the reference levels, i.e. two references that are two LSB apart, in order to compare the input signal against the reference levels. This can further reduce the overall area of the ADC in addition to input referred offset compensation for the comparators.

In some embodiments, the first capacitor bank and/or the second capacitor bank comprises a pair of parallel capacitors and switching arrangements. In this context, the switching arrangements are configured to be operable such that at least one capacitor of the pair of parallel capacitors stores a charge proportional to two least significant bit (LSB) in addition to an offset error of the amplifier. Furthermore, the switching arrangements are configured to be operable such that at least one capacitor of the pair of parallel capacitors stores a charge proportional to the offset error of the amplifier. Moreover, the switching arrangements are configured to be operable such that the pair of parallel capacitors each store a charge proportional to one least significant bit (LSB). This effectively provides two references that are two LSB apart for the ADC to compare the input signal against the references.

In some embodiments, the pair of parallel capacitors of the first capacitor bank and/or the second capacitor bank are equal in dimension (e.g., identical parallel plate capacitors). Additionally, the digital logic circuit may be configured to generate control signals for the switching arrangements of the first capacitor bank and/or the second capacitor bank. This may provide a straightforward arrangement for storing the references.

According to a second aspect of the disclosure, a method for signal conversion is provided in a system for analog-to-digital signal conversion. The method comprises the step of providing an analog input signal. The method further comprises the step of generating a reference signal by a digital-to-analog converter. In addition, the method comprises the step of generating an error signal comprising a difference between the analog input signal and the reference signal and amplifying the error signal by an amplifier. Furthermore, the method comprises the step of comparing the error signal with respect to a first reference level and a second reference level and generating event-based reset signals corresponding to a plurality of sampling instances by a level-crossing based sampling circuit. Moreover, the method further comprises the step of generating reset signals asynchronous to the event-based reset signals by a trigger circuit.

Therefore, the disclosure proposes additional resets for resetting the DAC in addition to the event-based resets correspond to each sampling instances, i.e. to each instances of sample generation, which can effectively minimize the requirement for a longer hold time of the DAC. Moreover, the offset requirements of the comparators are relaxed by the gain of the amplifier, which is shared by both comparators.

In some embodiments, the method further comprises the step of providing a first capacitor bank comprising a pair of parallel capacitors and switching arrangements in order to store the first reference level and providing a second capacitor bank comprising a pair of parallel capacitors and switching arrangements in order to store the second reference level.

In some embodiments, the method further comprises the step of operating the switching arrangements of the first capacitor bank and/or of the second capacitor bank for storing, by at least one capacitor of the pair of capacitors, a

charge proportional to two least significant bit (LSB) in addition to an offset error of the amplifier, and for storing, by at least one capacitor of the pair of capacitors, a charge proportional to the offset error of the amplifier, and for storing, by each of the pair of capacitors, a charge proportional to one least significant bit (LSB). This effectively provides two references that are two LSB apart for the ADC to compare the input signal against the references.

BRIEF DESCRIPTION OF THE DRAWINGS

Example embodiments are now further explained with respect to the drawings by way of example only, and not for limitation.

FIG. 1A shows a level-crossing based analog-to-digital converter, according to the prior art.

FIG. 1B shows sampling instances of the level-crossing based analog-to-digital converter of FIG. 1A, according to the prior art.

FIG. 2 shows a system, according to example embodiments.

FIG. 3A shows a trigger circuit, according to example embodiments.

FIG. 3B shows operation stages of the trigger circuit of FIG. 3A, according to example embodiments.

FIG. 4A shows the leakage induced error caused by a finite hold time of a digital-to-analog converter, according to example embodiments.

FIG. 4B shows the mitigation technique for the leakage induced error caused by a finite hold time of a digital-to-analog converter, according to example embodiments.

FIG. 5A shows a trigger circuit, according to example embodiments.

FIG. 5B shows output pulses of the trigger circuit of FIG. 5A, according to example embodiments.

FIG. 6 shows switched-capacitor arrangements for storing the reference levels, according to example embodiments.

FIG. 7 shows a system, according to example embodiments.

FIG. 8 shows a method, according to example embodiments.

DETAILED DESCRIPTION

Reference will now be made in detail to the embodiments, examples of which are illustrated in the accompanying drawings. However, the following embodiments may be variously modified and the range of the present disclosure is not limited by the following embodiments.

Along FIG. 1A and FIG. 1B, the operation of a conventional level-crossing based analog-to-digital converter is illustrated. Particularly, FIG. 1A shows a conventional level-crossing analog-to-digital converter (LC-ADC) that converts the analog signal V_{in} into discrete samples at a numerous sampling instances. Specifically, the LC-ADC uses level-crossing detection to sample the analog signal V_{in} . The LC-ADC consists of two comparators **104**, **105**, a digital-to-analog converter (DAC) **101** and a logic block **106** comprising an up/down counter. Two threshold levels V_H and V_L are set to identify the analog signal V_{in} . The threshold levels V_H and V_L are generated via the DAC **101** with a difference equal to the quantization step. Hence, in digital representation, the difference between V_H and V_L is equal to 2 least significant bit (LSB). The error **102** between V_{in} and V_H is fed to the comparator **104** and the error **103** between V_{in} and V_L is fed to the comparator **105** for comparison, for example.

The sampling instance or sampling occurs when V_{in} is either higher than V_{in} or lower than V_L . The logic block **106** then sets an increment signal or a decrement signal accordingly to activate the up/down counter, thereby incrementing or decrementing the counter output by 1 LSB. This further controls the DAC **101** whose generated signals V_H and V_L will be updated to keep tracking the analog signal V_{in} . On the other hand, as long as the analog signal V_{in} is between V_H and V_L , no changes occur on the up/down counter output or DAC **101** output, therefore no new samples are taken. The sampling instances are further shown in FIG. 1B, where the analog signal V_{in} is sampled at different instances, e.g. **107**, based on a sampling window **108** defined by the difference between V_H and V_L .

However, the two comparators **104,105** have a different offset voltage, which degrades the SNDR and therefore may be kept small in order to achieve a high SNDR. One possible option is to add a foreground calibration, especially a resistive calibration DAC that can permanently hold the reference voltage. However, this may come with the cost of increased power consumption and may further increase the overall area based on the use of an additional clock. Moreover, such a calibration scheme is not able to counter offset drifts, which might hinder the performance in a real application.

Using a capacitive DAC for the reference voltage generation is the most common architecture for LC-ADC due to its small area and power consumption. The problem with a capacitive DAC however is that it is not possible to hold the charge indefinitely. Since the DAC **101** is only reset when the analog signal V_{in} crosses V_H or V_L , the DAC **101** is not reset when the analog signal V_{in} changes slowly. This results in the leakage induced error increasing and therefore degrades the SNDR, especially for low frequencies.

In FIG. 2, a first example embodiment of the system **200** according to the first aspect of the disclosure is illustrated. The system **200** (can also be referred to as an analog-to-digital converter) comprises an analog input signal **201** to be converted into discrete samples while a reference signal **203** is generated by a digital-to-analog converter (DAC) **202** for domain conversion. The analog input signal **201** and the reference signal **203** are summed at a subtractor **204**, which results in an error or difference signal (voltage, charge or current) **205** comprising a difference between the analog input signal **201** and the reference signal **203**. The error signal **205** is fed to an amplifier or a pre-amplifier **206** that amplifies the error signal by the gain of the amplifier **206**. Hence, the amplifier **206** may mitigate any signal loss due to the subtraction of the analog input signal **201** and the reference signal **203** at the subtractor **204**.

The amplifier **206** provides a common node **207** at its output, which commonly shares the common node **207** with a first path **210** connecting to a non-inverting input of a first comparator **214** and a second path **211** connecting an inverting input of a second comparator **215**. A first capacitor bank **208** is located at the first path **210** between the common node **207** and the non-inverting input of the first comparator **214**. A second capacitor bank **209** is located at the second path **211** between the common node **207** and the inverting input of the second comparator **215**. An inverting input of the first comparator **214** and a non-inverting input of the second comparator **215** are commonly connected to ground. The first capacitor bank **208** and the second capacitor bank **209** each comprise a pair of parallel capacitors (not shown) and switching arrangements, whose functionalities will be discussed in a later section of this description.

The output **216** of the first comparator **214** and the output **217** of the second comparator **215** are connected to a digital logic circuit **218**. The digital logic circuit **218** includes an up/down counter and a timer (e.g. time-to-digital converter). The first capacitor bank **208**, the second capacitor bank **209**, the first comparator **214**, the second comparator **215**, and the digital logic circuit **218** collectively form a level-crossing based sampling circuit **220**. The sampled output **219** from the digital logic circuit **218** is fed back to the DAC **202** over a feedback path **222** in order to generate the reference signal **203**. The digital logic circuit **218** further outputs event-based reset signals **221** for each sampling instance or samples (i.e. up/down event) in order to reset the DAC **202**.

The system further comprises a triggering arrangement **230** for resetting the DAC **202** in addition to the event-based reset signals **221**. The triggering arrangement **230** includes a trigger circuit **223** that generates reset signals **224** asynchronous to the event-based reset signals **221**. The triggering arrangement **230** further comprises a two-input OR gate **225** that inputs the event-based reset signals **221** from the digital logic circuit **218** and the trigger signals **224** from the trigger circuit **224**, thereby outputting a trigger signal **226** whenever either one or both of the inputs of the OR gate **225** is high. It is to be noted that the OR gate **225** can be implemented with any logical combinations or gates as long as the output of the combinations is high when either one or both of the inputs are high.

Generally, the error signal **205** is amplified by the amplifier **206** and is further compared with a first reference level stored at the first capacitor bank **208** by the first comparator **214**. In some embodiments, the first reference level gives the upper boundary of the comparison window. Similarly, the error signal **205** is amplified by the amplifier **206** and is further compared with a second reference level stored at the second capacitor bank **209** by the second comparator **215**. In some embodiments, the second reference level gives the lower boundary of the comparison window. The storing method of the reference levels at the first capacitor bank **208** and at the second capacitor bank **209** will be discussed later in detail. The event-based reset signals **221** from the digital logic circuit **218** further change the reference signal level by shifting the first reference level and the second reference level via the DAC **202**, thereby shifting the comparison window for subsequent comparisons.

In other words, the first comparator **214** and the second comparator **215** respectively compare the error signal **205** with respect to a fixed comparison window, i.e. in digital representation of 2 LSB, and toggles its output whenever it detects a level crossing. This result in the generation of respective sampling instances or samples and further toggles the up/down counter to generate an up or down event. Since the first comparator **214** and the second comparator **215** compare the error signal **205** instead of the input analog signal **201**, the comparator common-mode range is reduced significantly and optimization of the comparators targeting at a specific reference level can be performed with ease. The related effects that result from comparator offset and distortion are thus reduced. More importantly, similar performance is achievable for the comparators with lower power consumption.

In addition, the amplifier **206** is shared by the first comparator **214** and the second comparator **215**. Thus, any error made after the amplifier **206** is divided by the gain of the amplifier **206**, which relaxes the offset requirement of the first comparator **214** and the second comparator **215**.

When the first comparator **214** and/or the second comparator **215** detect a level crossing with respect to the

comparison window, the output of the first comparator **214** and/or the output of the second comparator **215** toggle and the digital control circuit **218** updates the up/down counter in order to refresh the comparison window, thereby resetting the DAC **202**. The up/down counter acts as a digital integrator and the time in between two sampling instances are recorded by the timer.

In addition to the up and/or down event-based reset signals **221**, the trigger circuit **223** further generates asynchronous trigger signals **224**, which are cumulatively operating on the DAC **202** to reset the DAC **202**, even when there is no sampling instances recorded at the digital logic circuit **218**.

Along FIG. 3A and FIG. 3B, a first example embodiment of the trigger circuit is illustrated. In particular, FIG. 3A shows the trigger circuit **300**, which can be implemented as the trigger circuit **223** of FIG. 2. FIG. 3B shows operation stages of the trigger circuit **300**.

In some embodiments, the DAC **202** is a capacitive DAC, and the trigger circuit **300** may replicate the capacitive DAC. Since the leakage cannot be directly measured in the DAC **202**, the replica circuit **300** is able to sense the leakage and further to act accordingly to mitigate the leakage. The trigger circuit **300** comprises a capacitor **301** connected to ground at one node and further provides a common port **A** to the other node. At the common node **A**, a NMOS switch **302** is coupled. Particularly, the drain of the NMOS switch is coupled to the common node **A** whereas the source of the NMOS switch is coupled to a node **B**. A second switch **304** is coupled to the node **B** that initially connects the node **B** to a bias voltage V_{DD} . A comparator **303** is coupled to the common node **A** and the output **OUT** of the comparator **303** is fed back to the gate of the NMOS switch **302** and further used to toggle the second switch **304** between the bias voltage V_{DD} and ground **305**.

During normal operation, the output **OUT** is low. Due to leakage through the NMOS switch **302**, the voltage of the capacitor **301** rises. When the voltage of the capacitor **301** exceeds the trip point of the comparator **303**, the output **OUT** goes high. This causes the NMOS switch **302** to turn on and the second switch **304** to toggle to ground **305**. The capacitor **301** then discharges through the NMOS switch **302** and the voltage on the capacitor goes low again. This further sets the output **OUT** low and restarts the cycle.

The operation phases can be seen in FIG. 3B where the **OUT** is initially low and the voltage at **A** is rising, i.e. the charging state of the capacitor **301**. The voltage at **B** is at V_{DD} . When the voltage at **A** rises to the trip point of the comparator **303**, the comparator **303** output toggles, and thus **OUT** becomes high. At this point the capacitor **301** discharges and the voltage at **A** goes low as well as the voltage at **B**, since the latter is now connected to ground. This further sets the output **OUT** low and restarts the cycle. The **OUT** signals therefore represent the additional trigger signals **224** that are generated asynchronous to the event-based trigger signals **221** from the level-crossing based sampling circuit **220**.

Along FIG. 4A and FIG. 4B, the leakage induced error of a digital-to-analog converter and the proposed mitigation technique are illustrated. Particularly, FIG. 4A shows the leakage induced error caused by a finite hold time of the digital-to-analog converter **202**. As already mentioned before, a capacitive DAC is the most common architecture for the reference generation but suffers from a finite hold time. The signal V_{in} represents the analog input signal **201** which is sampled along a sampling window provided by the upper boundary or first reference level V_H and the lower

boundary or second reference level V_L . The event-based reset signals **221** are shown as spikes respective to each up/down events, i.e. sampling instances.

When the signal V_{in} changes sharply, more samples are generated, thereby generating more event-based reset signals **221**. Hence, for fast changing signals, the drift in the reference is very short and therefore the leakage induced error is not significant. However, when the signal changes slowly, less number of samples are generated, thereby less number of event-based reset signals **221**. This results in that the DAC reference drifts away and introduces a large leakage induced error. As it can be seen, the DAC **202** resets at point **401** and further drifts at **402** and further resets at **403**. Since the time between crossings is short, the leakage induced error is not significant. However, at **404**, the DAC drifts for a longer time that introduces a large leakage induced error.

FIG. 4B shows the proposed technique of having additional resets in order to mitigate the large leakage induced error in the DAC **202**. Additional trigger signals **224** are generated along with the event-based reset signals **221**, especially asynchronous to the event-based reset signals **221**. Hence, when the signal V_{in} is changing slowly, e.g. at **405** the DAC **202** resets and further drifts at **406**, however, is not drifting anymore due to the additional resets **224**. The DAC **202** resets at **407** instead. As a result, a portion of the leakage induced error is mitigated.

Along Figure 5A and FIG. 5B, a second example embodiment of the trigger circuit is illustrated. In particular, Figure 5A shows the trigger circuit **500**, which can be implemented as the trigger circuit **223** of FIG. 2. FIG. 5B shows the output of the trigger circuit **500**.

The requirements for an additional trigger generating circuit may be relaxed since exact timing may not be required. Therefore, the trigger circuit **223** can be implemented as a current starved ring oscillator circuit **500** as shown in FIG. 5A. The ring oscillator **500** comprises a first inverter stage **501**, a second inverter stage **502** and a third inverter stage **503**, where the output **504** of the third inverter stage **503** is fed back to the first inverter stage **501**. Although three inverter stages are illustrated herein, it is to be noted that any odd number of inverter stages can be implemented as long as the total propagation delay, i.e. the frequency of oscillation, meets the target specification. Hence, by connecting together any odd number of inverters to form a ring circuit, and by connecting the output of the ring straight back to the input of the ring, the circuit will continue to oscillate as a logic level "1" constantly rotates around the network. The oscillating outputs **OUT** can be seen in FIG. 5B, which represent the trigger signals **224** additionally generated to the event-based trigger signals **221**.

In FIG. 6, the first capacitor bank **208** and the second capacitor bank **209** are shown in detail. It is to be noted that the implementation is illustrated as a single-ended implementation and it is applicable to both capacitor banks **208**, **209**. Each capacitor bank comprises a pair of parallel capacitors **601** and **602**, and at least four switches S_1 , S_2 , S_3 and S_4 . The capacitors **601** and **602** are equally sized capacitors. Particularly, the amplifier **206** output is connected to one end of the capacitor **601** and the other end of the capacitor **601** is connected to the switches S_1 and S_4 , where the switch S_1 can be toggled to ground **603**. On the other hand, the switch S_2 is connected in parallel with the capacitor **602** to the switch S_4 and the switch S_3 is connected in series with the capacitor **602**, where the switch S_3 can be toggled to ground **604**. The first path **210** and/or the second

path **211**, as shown in FIG. 2, is coupled at the parallel junction between the switch S_4 , the switch S_2 and the capacitor **602**.

Along FIG. 6 the steps or phases for storing the reference level at the respective capacitor bank are illustrated in detail. During a first phase or step, S_1 is toggled to ground **603**, S_4 is opened (i.e. no conduction through the switch), S_2 is opened, and S_3 is closed (i.e. conduction through the switch). During this phase, no input analog signal **201** is inputted to the subtractor **204** and the DAC **202** generates reference voltage corresponding to the digital representation of 2 least significant bit (LSB). The amplifier **206** amplifies the 2 LSB along with an input referred offset **600** of the amplifier **206** by the gain A. Therefore, the output of the amplifier **206** during the first phase is given as:

$$V_{amp_1st} = A \times (2V_{LSB} + e) \quad (1)$$

where, A is the amplifier gain, V_{LSB} is the DAC reference voltage, and e is the input referred offset of the amplifier **206**.

Since S_4 is opened and S_1 is grounded, the capacitor **601** will store the charge equivalent to the amplifier **206** output.

$$Q_{C1} = -A \times C \times (2V_{LSB} + e) \quad (2)$$

where, Q_{C1} is the charge stored in the capacitor **601**, C is the capacitance of the capacitor **601**. The negative sign represents the change in the direction of the stored reference voltage, i.e. the polarity of the capacitor **601** is reversed.

During a second phase or step, S_1 is opened, S_4 is kept open, however S_2 is closed and S_3 is connected to the ground **604**. During this phase no analog input signal as well as no reference signal are inputted to the subtractor **204**. Therefore, the amplifier **206** amplifies only the input referred offset **600** by the gain A. Hence, the output of the amplifier **206** during the second phase is given as:

$$V_{amp_2nd} = A \times e \quad (3)$$

Since S_2 is closed and S_3 is grounded, the capacitor **602** will store the charge equivalent to the amplifier **206** output.

$$Q_{C2} = A \times C \times e \quad (4)$$

where, Q_{C2} is the charge stored in the capacitor **602**, C is the capacitance of the capacitor **602**, similar to the capacitor **601** as they are equally sized capacitors. Note that the signal is stored in the same direction of the amplifier output, therefore bearing no negative sign. Thus the polarity of the capacitor **602** is opposite to the polarity of the capacitor **601**.

During a third phase or step, S_1 is opened, S_4 is closed, however S_2 is opened and S_3 is closed again. During this phase, the system performs the normal operation, i.e. the analog input signal **201** and the reference signal **203** are inputted to the subtractor **204**. Thus, the amplifier **206** amplifies the difference or error signal along with the input referred offset **600**. Hence, the output of the amplifier **206** during the third phase is given as:

$$V_{amp_3rd} = A \times (V_{in} - V_{ref} + e) \quad (5)$$

Where, V_{in} is the analog input signal **201** and V_{ref} is the reference signal **203** generated from the DAC **202**.

However, since S_4 is now closed, the capacitors **601** and **602** will share their charges as stored in the first phase and the second phase, respectively. This results in the cancellation of the input referred offset due to their opposite polarity. Moreover, each of the capacitor **601** and **602** now stores a charge equivalent to 1 LSB, which is given by:

$$Q_{C1} = Q_{C2} = -A \times C \times V_{LSB} \quad (6)$$

Therefore, the respective comparators compare the output of the amplifier **206** with respect to the reference level correspondingly stored at the respective capacitor banks **208**, **209**. In some embodiments, the digital logic circuit **218** provides the control signals used to toggle the switches S_1 , S_2 , S_3 , and S_4 , which can be generated from a sequence of logic based on the different phases described above and/or can be pre-programmed and further can be executed before and during the signal conversion.

In FIG. 7, a second example embodiment of the system **700** according to the first aspect of the disclosure is illustrated. The system **700** differs from the system **200** in that the reference levels are separately inputted through an additional amplifier as opposed to input via a shared amplifier and to store the reference levels in two capacitor banks.

The system **700** comprises the analog input signal **201** to be converted into discrete samples while the reference signal **203** is generated by the DAC **202** for domain conversion. The analog input signal **201** and the reference signal **203** are summed at the subtractor **204**, which results in the error or difference signal (voltage, charge or current) **205** comprising a difference between the analog input signal **201** and the reference signal **203**. The error signal **205** is fed to the amplifier or the pre-amplifier **206** that amplifies the error signal by the gain of the amplifier **206**.

The output of the amplifier **206** is fed to the non-inverting input of the first comparator **214** and further to the inverting input of the second comparator **215**. In addition, a reference level **701** is inputted to an additional amplifier **706**, where the output of the amplifier **706** is fed to the inverting input of the first comparator and further to the non-inverting input of the second comparator, however the latter input is inverted by an inverter **708**. Hence, the amplifier **206** provides the error signal **205** whereas the amplifier **706** provides the reference levels for the comparison window. It is to be noted that the amplifier **706** is selected so as to match the gain of the amplifier **206**. The level-crossing based sampling as well as the additional trigger generation as described along FIG. 2 are analogously performed in the system **700**, and are not repeated herein.

In FIG. 8, an example embodiment of the method **800** according to the second aspect of the disclosure is illustrated. In a first step **801**, an analog input signal is provided. In a second step **802**, a reference signal is generated. In a third step **803**, an error signal is generated that comprises a difference between the analog input signal and the reference signal. In a fourth step **804**, the error signal is compared with respect to a first reference level and to a second reference level. In a fifth step **805**, event-based reset signals are generated corresponding to a plurality of sampling instances. In a sixth step **806**, additional reset signals asynchronous to the event-based reset signals are generated.

The embodiments of the present disclosure can be implemented by hardware, software, or any combination thereof. Various embodiments may be implemented by one or more application specific integrated circuits (ASICs), digital signal processors (DSPs), digital signal processing devices (DSPDs), programmable logic devices (PLDs), field programmable gate arrays (FPGAs), processors, controllers, microcontrollers, microprocessors, or the like.

Although example embodiments have been illustrated and described with respect to one or more implementations, equivalent alterations and modifications will occur to others skilled in the art upon the reading and understanding of this specification and the annexed drawings. In addition, while a particular feature may have been disclosed with respect to only one of several implementations, such feature may be

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combined with one or more other features of the other implementations for any given or particular application.

What is claimed is:

1. A system for analog-to-digital signal conversion comprising:
 - an analog input signal;
 - a digital-to-analog converter configured to generate a reference signal;
 - an amplifier configured to amplify an error signal comprising a difference between the analog input signal and the reference signal;
 - a level-crossing based sampling circuit comprising a first comparator configured to compare the error signal with respect to a first reference level, and a second comparator configured to compare the error signal with respect to a second reference level, thereby generating event-based reset signals corresponding to a plurality of sampling instances in order to reset the digital-to-analog converter and further to shift the first reference level and the second reference level through the digital-to-analog converter; and
 - a trigger circuit configured to generate reset signals asynchronous to the event-based reset signals in order to reset the digital-to-analog converter.
2. The system according to claim 1, wherein the level-crossing based sampling circuit further comprises a digital logic circuit configured to generate an amplitude and a time stamp corresponding to each of the plurality of sampling instances.
3. The system according to claim 2, wherein the digital logic circuit is further configured to feedback the amplitude corresponding to each of the plurality of sampling instances to the digital-to-analog converter in order to generate the reference signal.
4. The system according to claim 1, wherein the digital-to-analog converter is a capacitive charge transfer digital-to-analog converter or a switched capacitor based digital-to-analog converter.
5. The system according to claim 4, wherein the trigger circuit comprises a switched capacitor arrangement in order to replicate the digital-to-analog converter.
6. The system according to claim 1, wherein the level-crossing based sampling circuit further comprises a first capacitor bank coupled between a common node downstream to the amplifier and the first comparator, and wherein the first capacitor bank is configured to store the first reference level based on the reference signal.
7. The system according to claim 6, wherein the level-crossing based sampling circuit further comprises a second capacitor bank coupled between the common node downstream to the amplifier and the second comparator, and wherein the second capacitor bank is configured to store the second reference level based on the reference signal.
8. The system according to claim 7, wherein the first capacitor bank or the second capacitor bank comprises a pair of parallel capacitors and switching arrangements, and wherein the switching arrangements are configured to be operable such that at least one capacitor of the pair of parallel capacitors stores a charge proportional to two least significant bit (LSB) in addition to an offset error of the amplifier.

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9. The system according to claim 8, wherein the switching arrangements are further configured to be operable such that at least one capacitor of the pair of parallel capacitors stores a charge proportional to the offset error of the amplifier.
10. The system according to claim 8, wherein the switching arrangements are further configured to be operable such that the pair of parallel capacitors each stores a charge proportional to one least significant bit (LSB).
11. The system according to claim 8, wherein the pair of parallel capacitors of the first capacitor bank or the second capacitor bank are equal in dimension or are identical parallel plate capacitors.
12. The system according to claim 8, wherein the level-crossing based sampling circuit further comprises a digital logic circuit configured to generate an amplitude and a time stamp corresponding to each of the plurality of sampling instances, and wherein the digital logic circuit is further configured to generate control signals for the switching arrangements of the first capacitor bank or the second capacitor bank.
13. A method for analog-to-digital signal conversion comprising:
 - providing an analog input signal;
 - generating a reference signal by a digital-to-analog converter;
 - generating an error signal comprising a difference between the analog input signal and the reference signal;
 - amplifying the error signal by an amplifier;
 - comparing the error signal with respect to a first reference level and a second reference level;
 - generating event-based reset signals corresponding to a plurality of sampling instances by a level-crossing based sampling circuit; and
 - generating reset signals asynchronous to the event-based reset signals by a trigger circuit.
14. The method according to claim 13, wherein the method further comprises providing:
 - a first capacitor bank comprising a pair of parallel capacitors and switching arrangements in order to store the first reference level; and
 - a second capacitor bank comprising a pair of parallel capacitors and switching arrangements in order to store the second reference level.
15. The method according to claim 14, wherein the method further comprises operating the switching arrangements of the first capacitor bank or of the second capacitor bank for:
 - storing, by at least one capacitor of the pair of parallel capacitors, a charge proportional to two least significant bit (LSB) in addition to an offset error of the amplifier;
 - storing, by at least one capacitor of the pair of parallel capacitors, a charge proportional to the offset error of the amplifier; and
 - storing, by each of the pair of parallel capacitors, a charge proportional to one least significant bit (LSB).
16. The method according to claim 14, wherein the pair of parallel capacitors of the first capacitor bank or the second capacitor bank are equal in dimension or are identical parallel plate capacitors.
17. The method according to claim 13, wherein the level-crossing based sampling circuit comprises a digital

logic circuit configured to generate an amplitude and a time stamp corresponding to each of the plurality of sampling instances.

18. The method according to claim 17, wherein the digital logic circuit is further configured to feedback the amplitude 5 corresponding to each of the plurality of sampling instances to the digital-to-analog converter in order to generate the reference signal.

19. The method according to claim 13, wherein the digital-to-analog converter is a capacitive charge transfer 10 digital-to-analog converter or a switched capacitor based digital-to-analog converter.

20. The method according to claim 19, wherein the trigger circuit comprises a switched capacitor arrangement in order to replicate the digital-to-analog converter. 15

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